



SEMI® International Standards Program

Compound Semiconductor Technical Committee Meeting

Virtual Meeting (Videoconference)

Tuesday 14th April 2026,
16:00 CEST / 7:00 am PDT / 23:00 J

V2 24.02.2026

Co-chairs:

- [Dr. Arnd-Dietrich Weber, SiCrystal](#)
- [Dr. Christian Kranert, Fraunhofer IISB](#)

European Compound Semiconductor Committee Meeting (Virtual Meeting)

16:00	Welcome and Self-Introductions	all
16:05	SEMI Standards Overview and Legal Reminders	SEMI Staff
16:10	Review of the minutes and action items from the previous meeting	SEMI Staff
16:15	Task Force Reports (~5 minutes each) • SiC-Task Force • 5-year Review Task Force • Test Methods for SiC -Task Force • SiC Epi Defects Task Force • Silicon Carbide Engineered Substrate Task Force	A. Weber H.C. Alt C. Kranert C. Kranert E. Cela
16:35	Approval for Ballot: Guide for Defects found in Homoepitaxial Layers of Silicon Carbide	C. Kranert
16:45	Ballot Review: • Doc. 7416, Reapproval of SEMI M82-0820 Test Method for the Carbon Acceptor Concentration In Semi-Insulating Gallium Arsenide Single Crystals by Infrared Absorption Spectroscopy • Doc. 7111, Revision of SEMI M81-0418, Guide for Defects Found in Monocrystalline Silicon Carbide Substrates	A. Weber
17:25	Compound Materials Liaison Reports • North America • Japan • China	SEMI Staff
17:35	New Business: • Review of document-status and upcoming-reviews • Open discussion	A. Weber N.N.
17:40	Any Other Business / Questions	A. Weber
17:44	Next Meetings	
17:50	End	